

**Amendments to the Specification:**

**In the Title:** Please replace the title "PROBE STATION" with --PROBE STATION WITH TWO PLATENS--.

**On page 8,**

line 3, after "supports," change "112a, 112b, 112c, and 112d" to read: --112A, 112B, 112C, and 112D--.

**On page 11,**

line 2, after the first and second occurrences of "supports," change "212a-212d" to read --212A-212D--;

line 3, after "openings," "change 220a-220d" to read --220A-220D--;

line 4, after "supports," change "224a-224d" to read --224A-224D--;

line 5, after the first occurrence of "supports," change "224a-224d" to read --224A-224D--; and after the second occurrence of "supports," change "212a-212d" to read --212A-212D--.

**On page 13,**

line 4, after "supports," change "350a-350d" to read --350A-350D--;

line 5, after the first occurrence of "contacts," change 352a-352d" to read --352A-352D--; and after the second occurrence of "contacts," change "352a-352d" to read --352A-352D--;

line 8, after "supports," change "350a-350d" to read --350A-350D--;

line 10, after "supports," change "350a-350d" to read --350A-350D--;

lines 11-12, after "supports," change "350a-350d" to read --350A-350D--;

line 14, after the first occurrence of "supports," change 350a-350d" to read --350A-350D--; and after the second occurrence of "supports," change "350a-350d" to read --350A-350D--;

line 15, after "supports," change "350a-350d" to read --350A-350D--;

line 16, after "mechanism" change "358" to read --359--;

line 17, after "supports," change "350a-350d" to read --350A-350D--; and

line 21, after "supports," change "350a-350d" to read --350A-350D--.

Appl. No. 10/759,481  
Amdt. dated Jul. 13, 2005  
Reply to Office Action dated Feb. 17, 2005

**In the Abstract:** Please replace the following Abstract:

“A probe station.”

with the following:

--A probe station for testing a device under test. A first platen supporting an electrical probe. A chuck supporting the device under test. A second platen supporting an optical probe. The first platen and the second platen positioned above the device under test. A percentage of the top surface of the second platen terminating into free space.--